

Product Summary

$V_{(BR)DSS}$	$R_{DS(on)TYP}$	I_D
60V	36mΩ@10V	4.5A

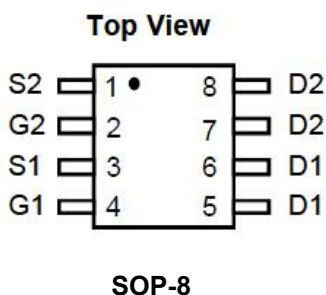
Feature

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high EAS
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

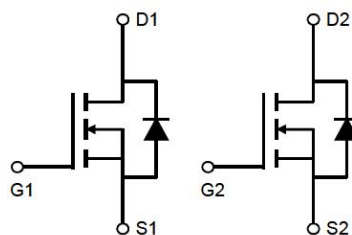
Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

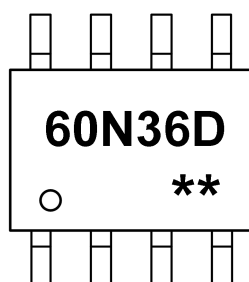
Package



Circuit diagram



Marking



60N36D =Device Code
****** =Week Code

**Absolute maximum ratings (Ta=25°C unless otherwise noted)**

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	4.5	A
Pulsed Drain Current ⁽¹⁾	I_{DM}	20	A
Power Dissipation	P_D	2	W
Thermal Resistance from Junction to Ambient ⁽²⁾	$R_{\theta JA}$	62.5	°C/W
Junction Temperature	T_J	150	°C
Storage Temperature	T_{STG}	-55~ +150	°C

Electrical characteristics (Ta=25 °C, unless otherwise noted)

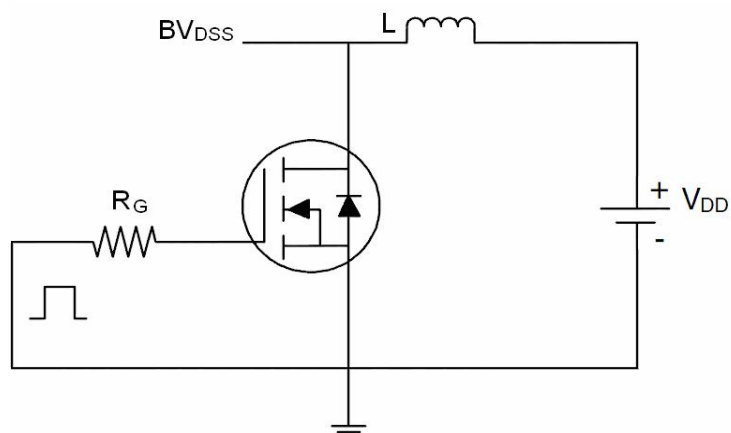
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	60	69	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =60V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
On Characteristics ⁽³⁾						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	1.2	2.0	2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =4.5A	-	36	45	mΩ
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =4.5A	11	-	-	S
Dynamic Characteristics ⁽⁴⁾						
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, F=1.0MHz	-	450	-	PF
Output Capacitance	C _{oss}		-	60	-	PF
Reverse Transfer Capacitance	C _{rss}		-	25	-	PF
Switching Characteristics ⁽⁴⁾						
Turn-on Delay Time	t _{d(on)}	V _{DS} =30V, I _D =4.5A V _{GS} =10V, R _{GEN} =3Ω	-	4.7	-	nS
Turn-on Rise Time	t _r		-	2.3	-	nS
Turn-Off Delay Time	t _{d(off)}		-	15.7	-	nS
Turn-Off Fall Time	t _f		-	1.9	-	nS
Total Gate Charge	Q _g	V _{DS} =30V, I _D =4.5A, V _{GS} =10V	-	8.5	-	nC
Gate-Source Charge	Q _{gs}		-	1.6	-	nC
Gate-Drain Charge	Q _{gd}		-	2.2	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage ⁽³⁾	V _{SD}	V _{GS} =0V, I _S =4.5A	-	-	1.2	V
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F =4.5A di/dt = 100A/μs ⁽³⁾	-	25	-	nS
Reverse Recovery Charge	Q _{rr}		-	35	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

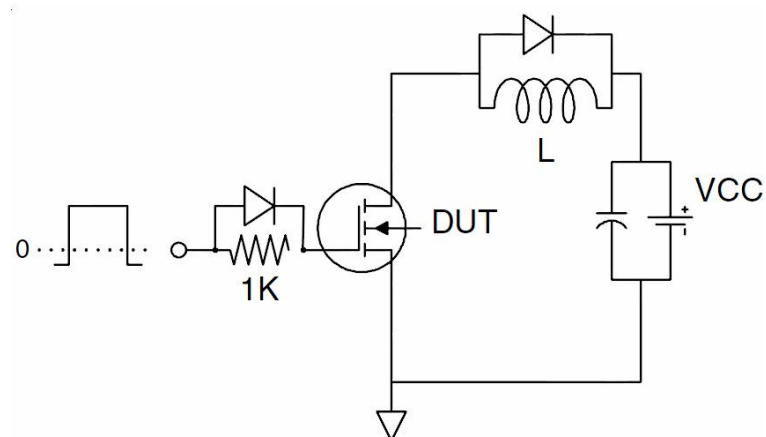
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production

Test Circuits

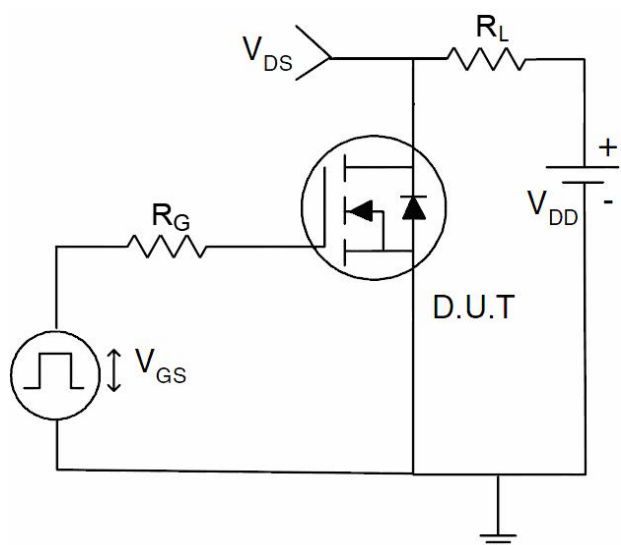
1) EAS Test Circuits



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





Typical Characteristics

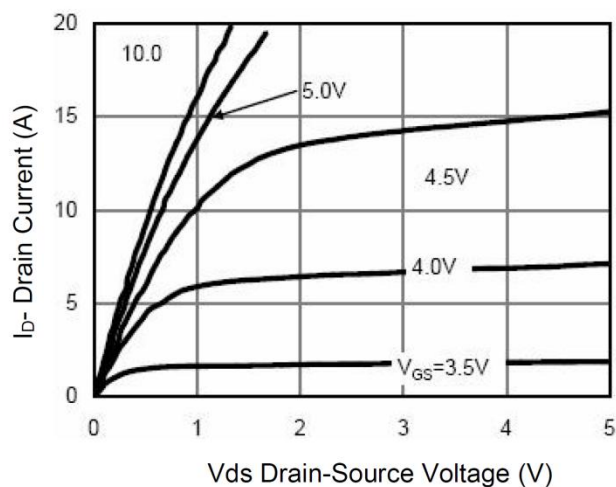


Figure 1 Output Characteristics

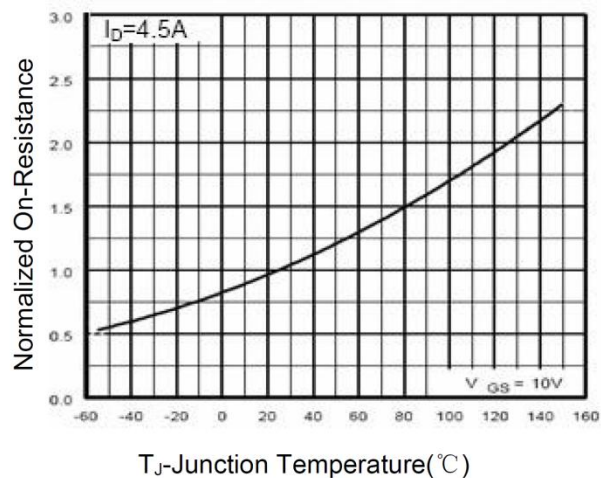


Figure 4 $R_{DS(on)}$ -Junction Temperature

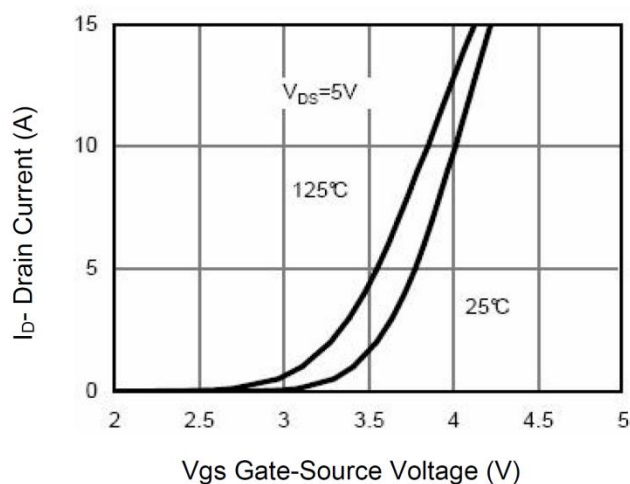


Figure 2 Transfer Characteristics

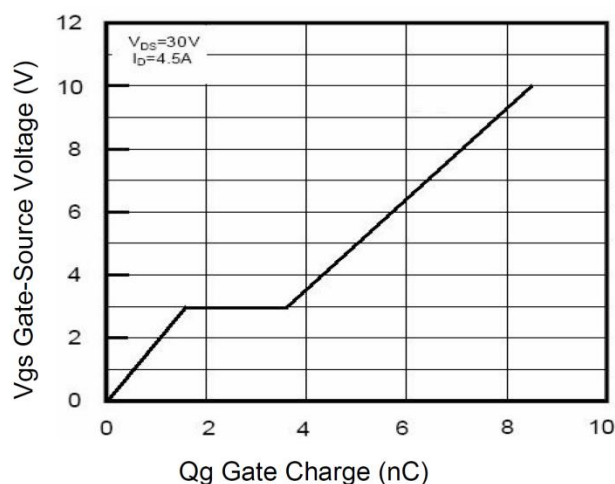


Figure 5 Gate Charge

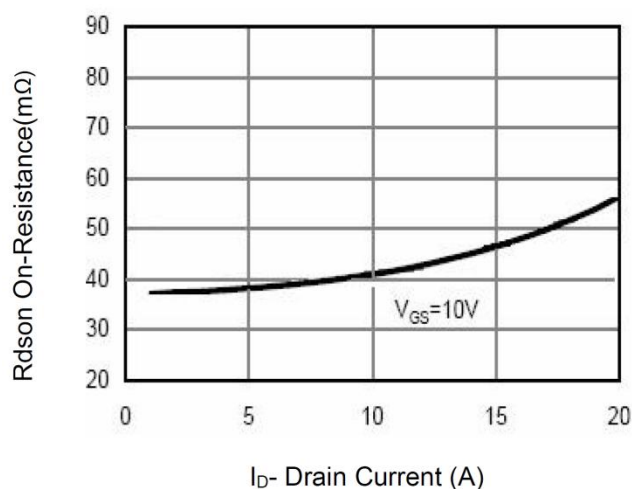


Figure 3 $R_{DS(on)}$ - Drain Current

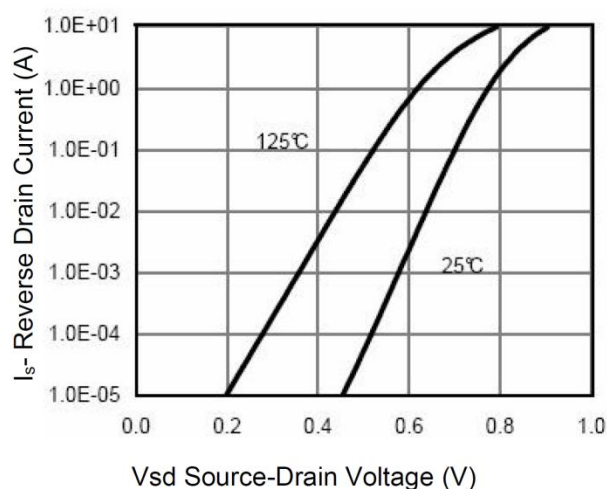


Figure 6 Source- Drain Diode Forward

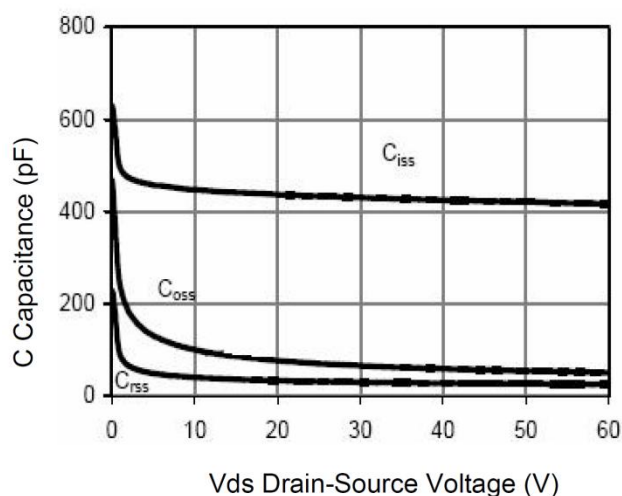


Figure 7 Capacitance vs Vds

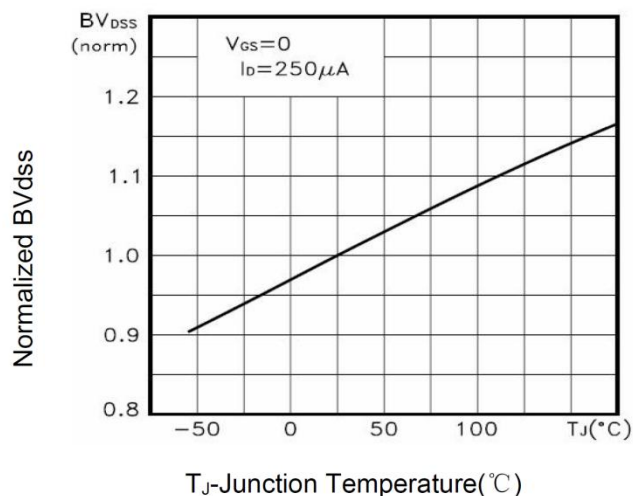


Figure 9 BV_{dss} vs Junction Temperature

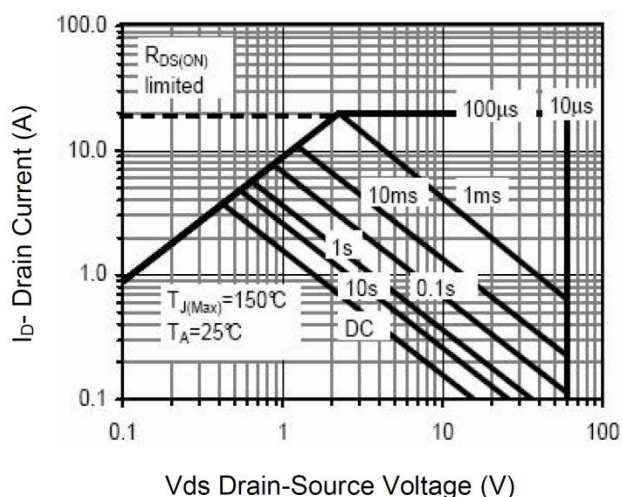


Figure 8 Safe Operation Area

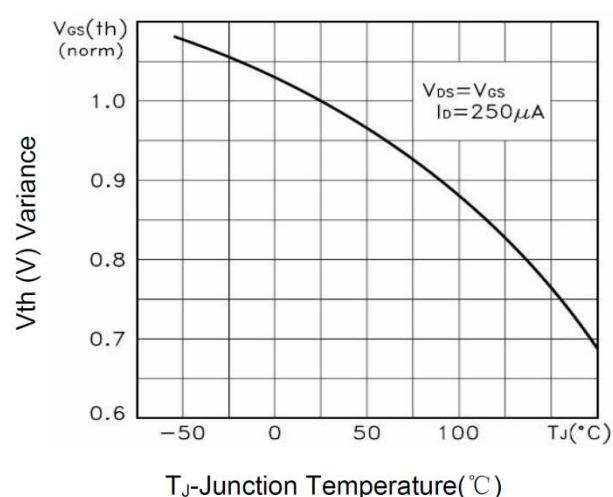


Figure 10 $V_{GS(th)}$ vs Junction Temperature

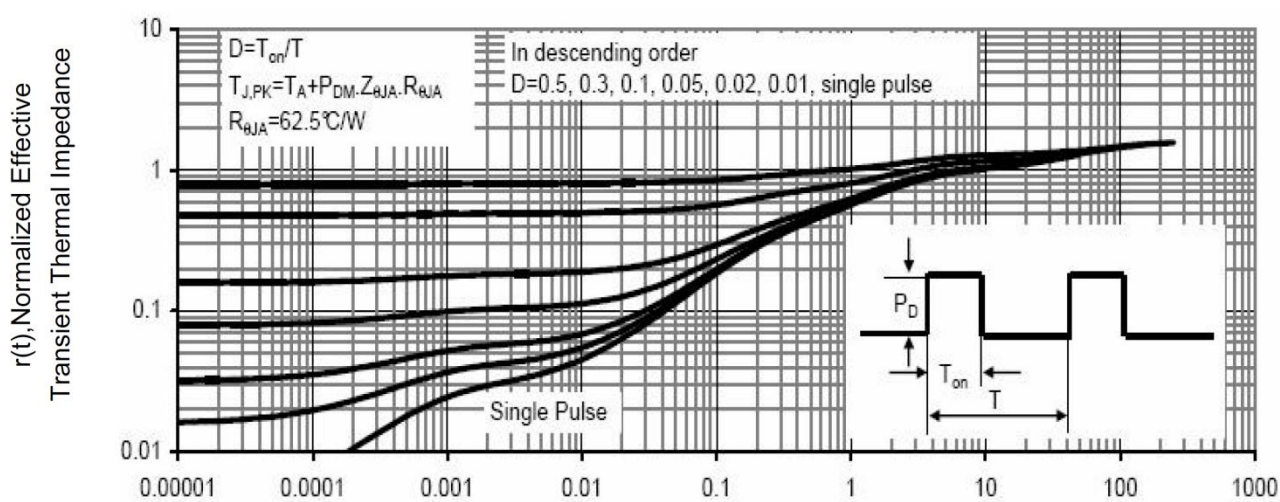
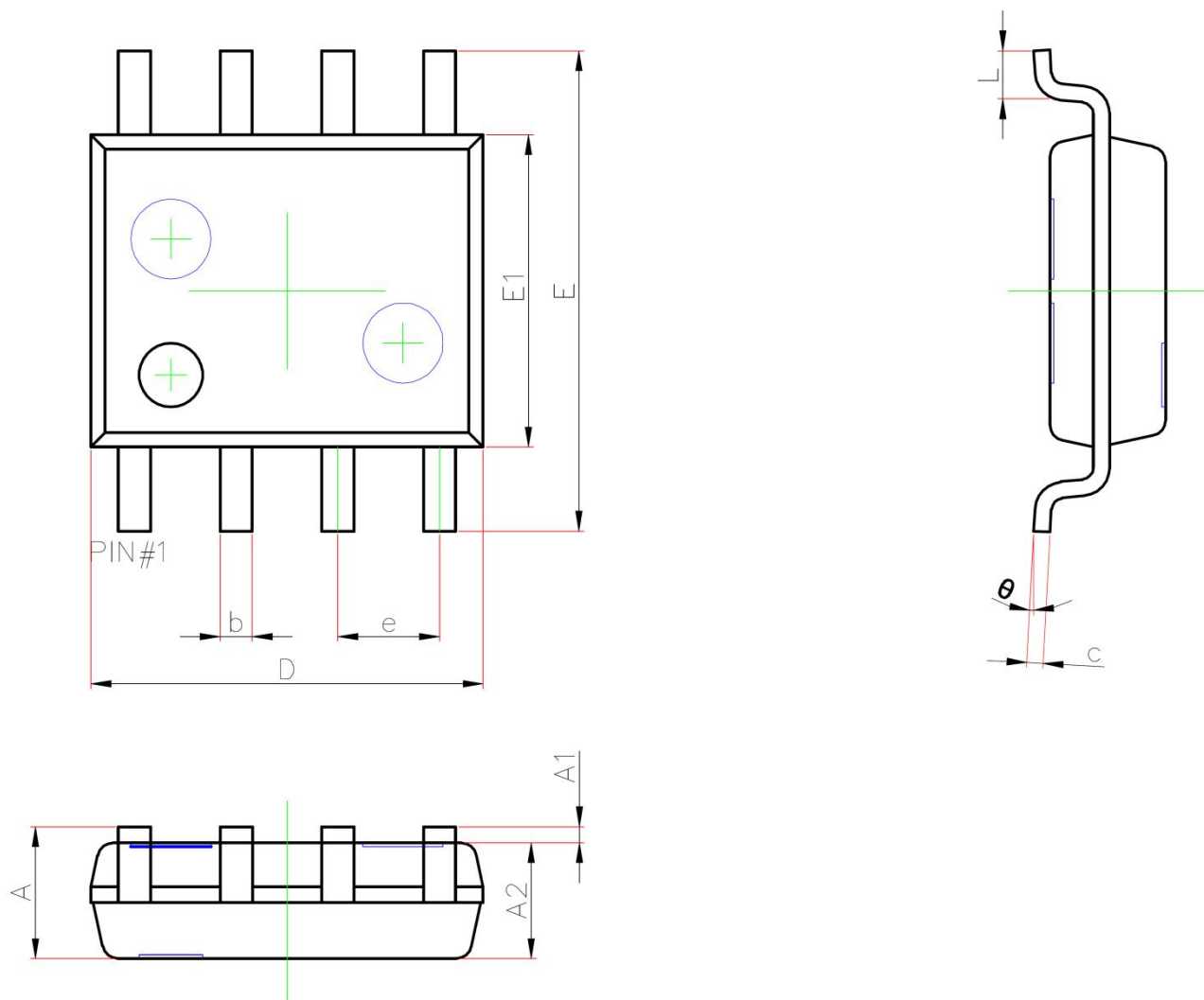


Figure 11 Normalized Maximum Transient Thermal Impedance

SOP-8 Package Information



Symbol	Dimensions In Millimeters	
	Min.	Max.
A	1.35	1.75
A1	0.10	0.25
A2	1.35	1.55
b	0.33	0.51
c	0.17	0.25
D	4.80	5.00
e	1.27 REF.	
E	5.80	6.20
E1	3.80	4.00
L	0.40	1.27
θ	0°	8°